

L Number	Hits	Search Text	DB	Time stamp
14	4879	(250/306,307,311,442.11).CCLS.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:02
15	13707	(sample or wafer or semiconductor) near observ\$7	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:02
16	0	((sample or wafer or semiconductor) near observ\$7) and (first near scale near (factor or value))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:03
17	0	((250/306,307,311,442.11).CCLS.) and (first near scale near (factor or value))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:03
18	224	(first near scale near (factor or value))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:04
19	15	((first near scale near (factor or value))) and (reference near (sample or image))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:04
20	0	(((first near scale near (factor or value))) and (reference near (sample or image))) and (bas\$2 with information with defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:05
21	5	(((first near scale near (factor or value))) and (reference near (sample or image))) and ((mov\$4 or position\$4) near (sample or wafer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:06
22	0	(((first near scale near (factor or value))) and (reference near (sample or image))) and ((mov\$4 or position\$4) near (sample or wafer)) and (imag\$4 near4 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:08
23	3072	(reference near (sample or image)) and imag\$4 and defect\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:12
24	0	((reference near (sample or image)) and imag\$4 and defect\$4) and (second adj (scale near (factor or value)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:20
25	29	(image near pickup) and (image near2 sample) and ((position\$3 or mov\$4) near2 sample) and defect	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:22
26	2	((image near pickup) and (image near2 sample) and ((position\$3 or mov\$4) near2 sample) and defect) and (locat\$5 near2 defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:23
27	0	(((image near pickup) and (image near2 sample) and ((position\$3 or mov\$4) near2 sample) and defect) and (locat\$5 near2 defect)) and (scale near (factor or value))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/13 15:24